

wake fields in undulator

bunch shape

2d geometry, **resistive effects**

round pipe

beam impedance, surface impedance

arbitrary cross section

flat pipe

surface

oxide layer

roughness

conductivity

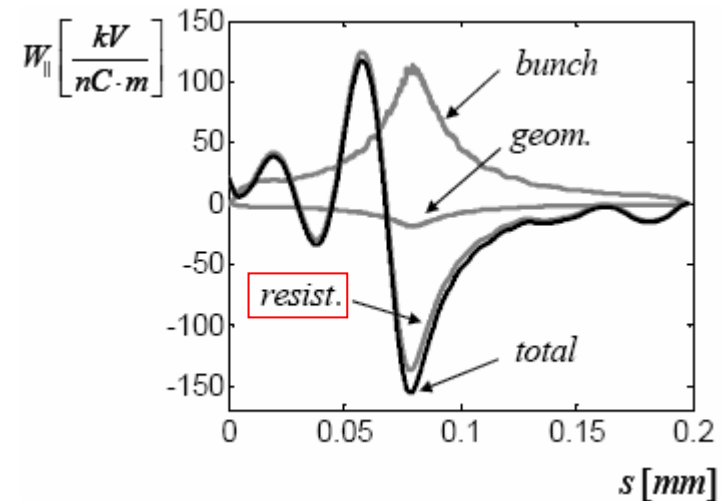
material → 2d geometry

anomalous skin effect

3d geometry

summary

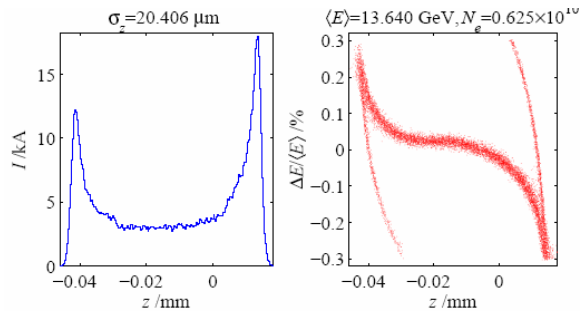
European XFEL undulator wake



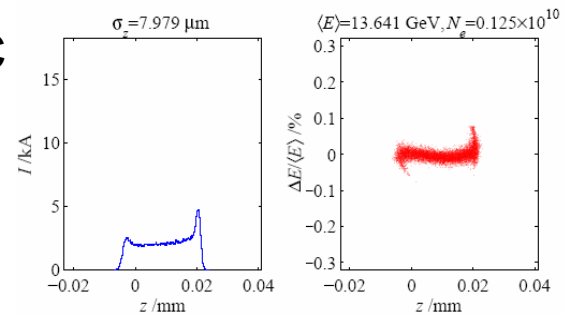
bunch shape

LCLS

1nC

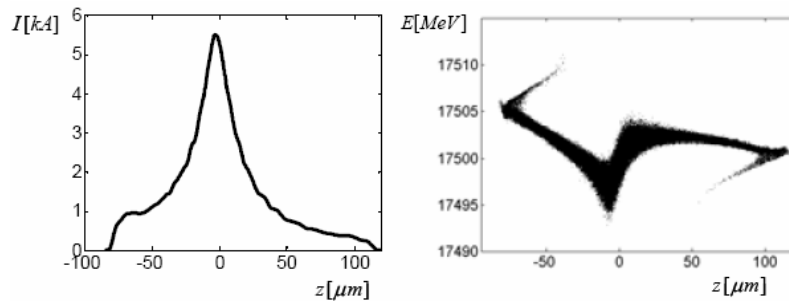


0.2nC



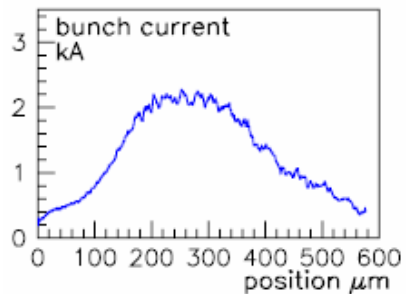
European XFEL

1nC



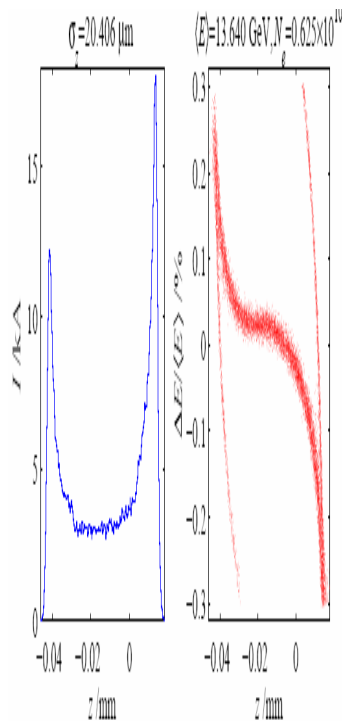
BESSY FEL

2.4nC

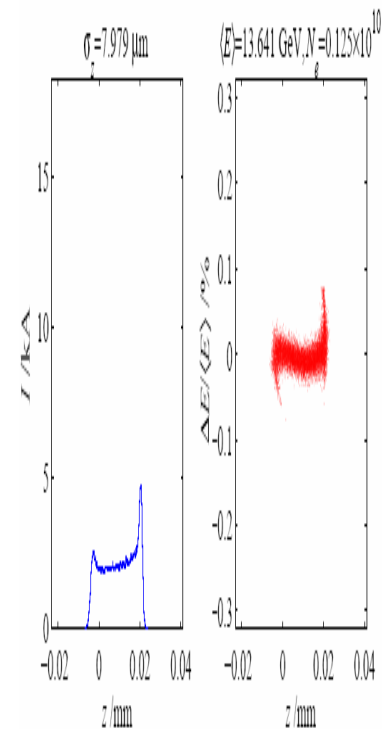


LCLS

1nC

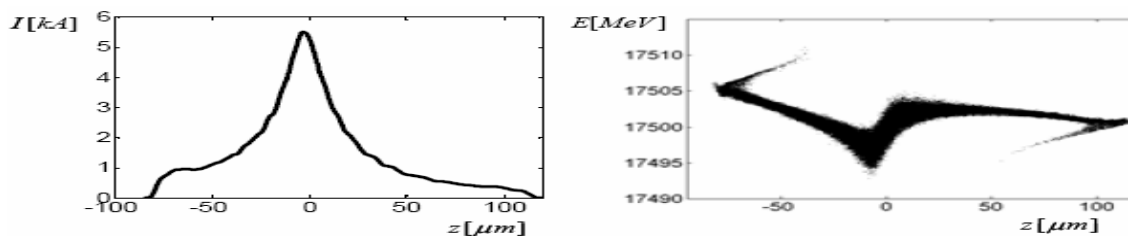


0.2nC



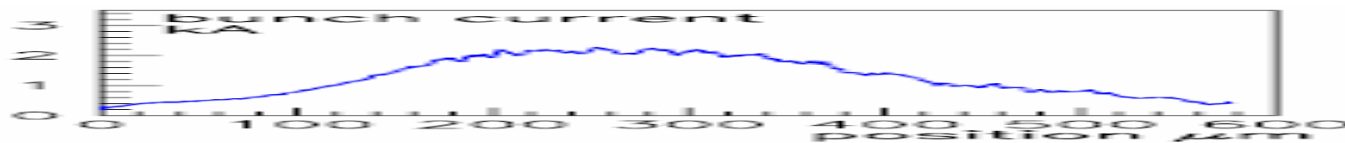
European XFEL

1nC



BESSY FEL

2.4nC



resistive wall effects:

characteristic length

$$S_{\text{ch}} = \left(\frac{R^2}{2\kappa_0 Z_0} \right)^{1/3}$$

example

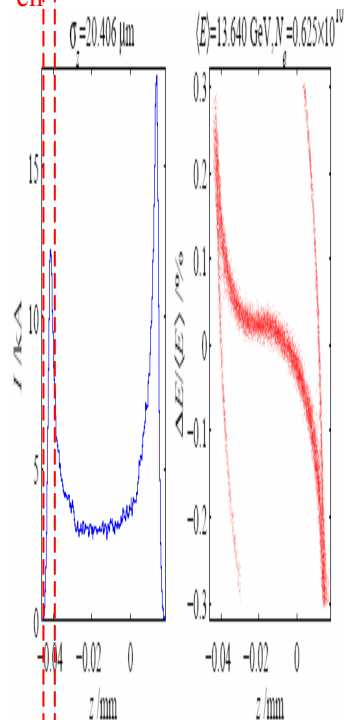
$$R = 3 \text{ mm}$$

$$\kappa_0 = 58 \text{ S/m}$$

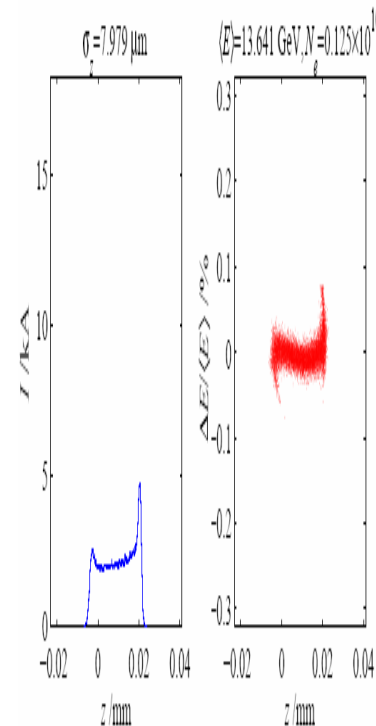
$$\rightarrow S_{\text{ch}} \approx 6 \mu\text{m}$$

S_{ch}

LCLS 1nC

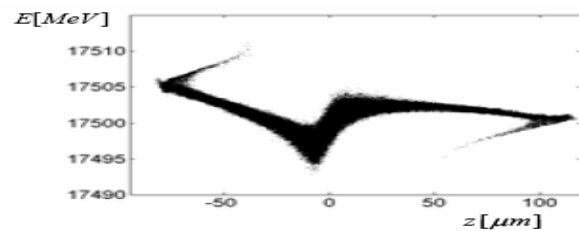
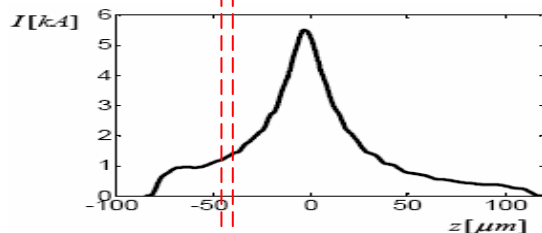


0.2nC



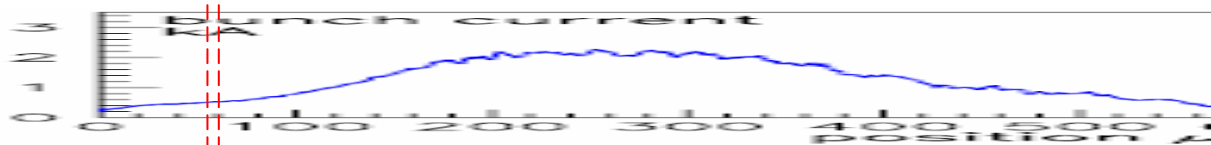
European XFEL

1nC



BESSY FEL

2.4nC

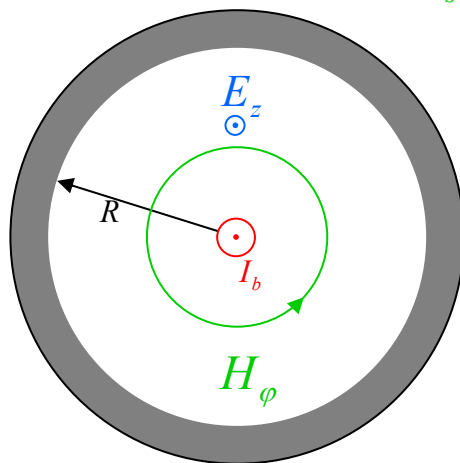


2d geometry: round pipe

beam impedance and surface impedance

$$Z'_b = - \left. \frac{E_z}{I_b} \right|_{r \rightarrow 0}$$

$$Z_s = - \left. \frac{E_z}{H_\varphi} \right|_{r=R}$$



$$\begin{array}{l}
 H_\varphi = \left[\frac{I}{2\pi r} \exp(i\omega(t - z/c)) \right] + \left[A \frac{r}{2} \exp(i\omega(t - z/c)) \right] \\
 E_r = \left[Z_0 \frac{I}{2\pi r} \exp(i\omega(t - z/c)) \right] + \left[Z_0 A \frac{r}{2} \exp(i\omega(t - z/c)) \right] \\
 E_z = \left[0 \right] + \left[- \frac{A}{i\omega\epsilon_0} \exp(i\omega(t - z/c)) \right]
 \end{array}$$

beam

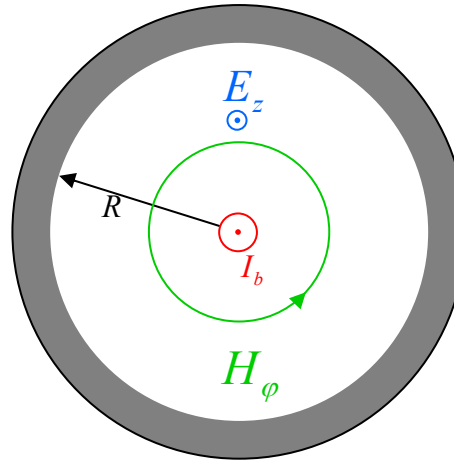
boundary



beam impedance and surface impedance

$$Z'_b = - \left. \frac{E_z}{I_b} \right|_{r \rightarrow 0}$$

$$Z_s = - \left. \frac{E_z}{H_\varphi} \right|_{r=R}$$



$$Z'_b(\omega) = \frac{Z_s(\omega)}{2\pi R} \frac{1}{1 + i \frac{\omega R}{c} \frac{Z_s(\omega)}{Z_0}}$$

metallic conductor (κ):
(plane wave approximation)

$$Z_s^{(\kappa)} = \sqrt{\frac{j\omega\mu}{\kappa(\omega) + j\omega\varepsilon}}$$

$$Z_s^{(\kappa)} \approx \sqrt{\frac{j\omega\mu}{\kappa(\omega)}}$$

$$\kappa(\omega) \approx \frac{\kappa_0}{1 + i\omega\tau}$$



asymptotic limit

$$Z'_b(\omega) = \frac{Z_s(\omega)}{2\pi R} \frac{1}{1 + i \frac{\omega R Z_s(\omega)}{c 2 Z_0}}$$

$$|\dots| = 1 \quad \rightarrow \quad \omega_{\text{ch}} = 2c \left(\frac{\kappa_0 Z_0}{2R^2} \right)^{1/3} \quad S_{\text{ch}} = \sqrt[3]{2} \frac{c}{\omega_{\text{ch}}}$$

low frequency $\omega \ll \omega_{\text{ch}}$

$$Z'_b(\omega) \approx \frac{Z_s(\omega)}{2\pi R} \approx \frac{1}{2\pi R} \sqrt{\frac{i\omega\mu}{\kappa_0}}$$

$\sim \sqrt{\omega}$
 $\sim 1/\sqrt{\kappa}$
 $\sim 1/R$

high frequency $\omega \gg \omega_{\text{ch}}$

$$Z'_b(\omega) \rightarrow \frac{1}{\pi R^2 \epsilon_0} \frac{1}{i\omega}$$

capacitive impedance
 material independent
 $\sim 1/R^2$

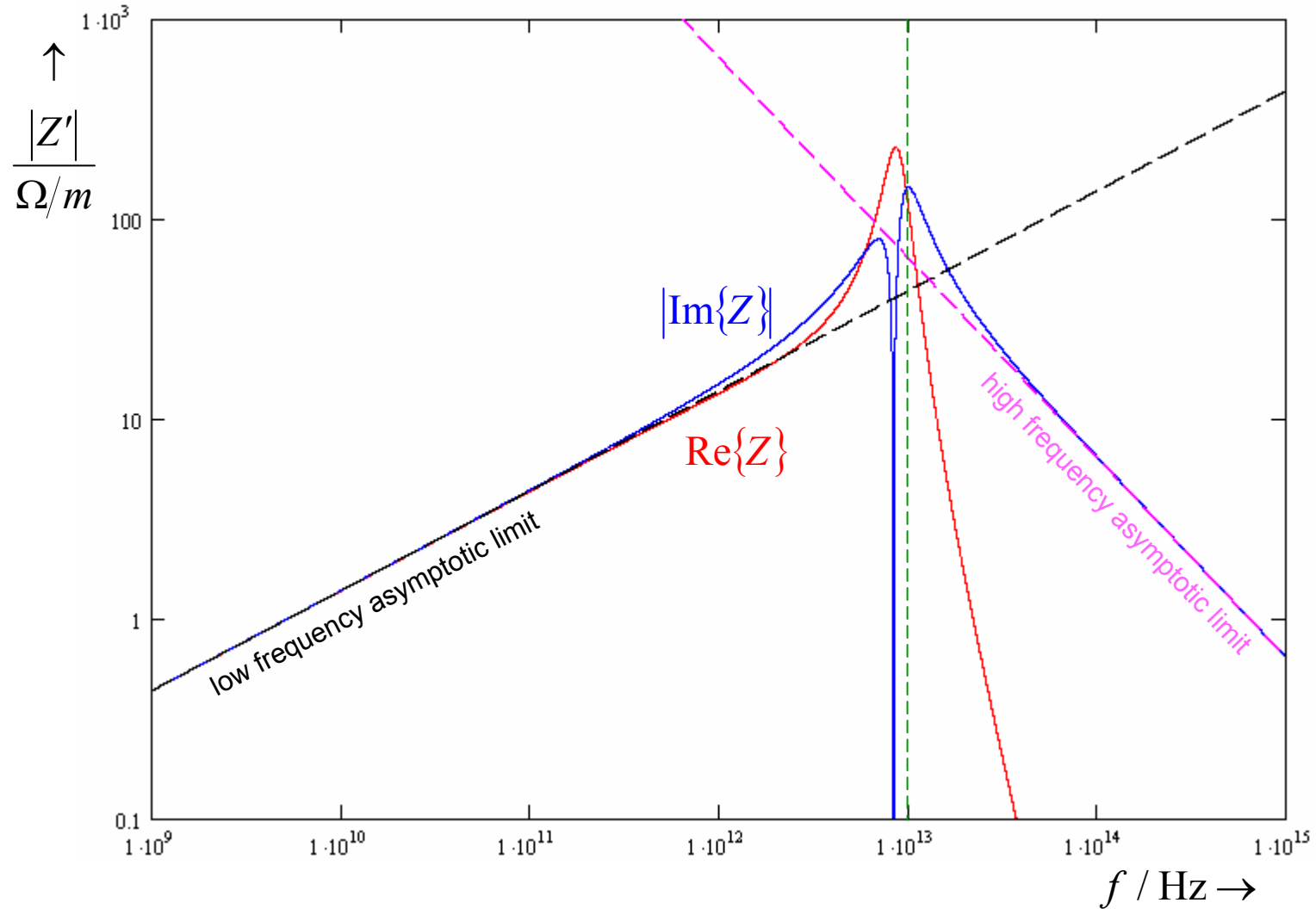


copper, R = 3mm

$$\kappa_0 = 58 \cdot 10^6 \frac{1}{\Omega \text{m}}$$

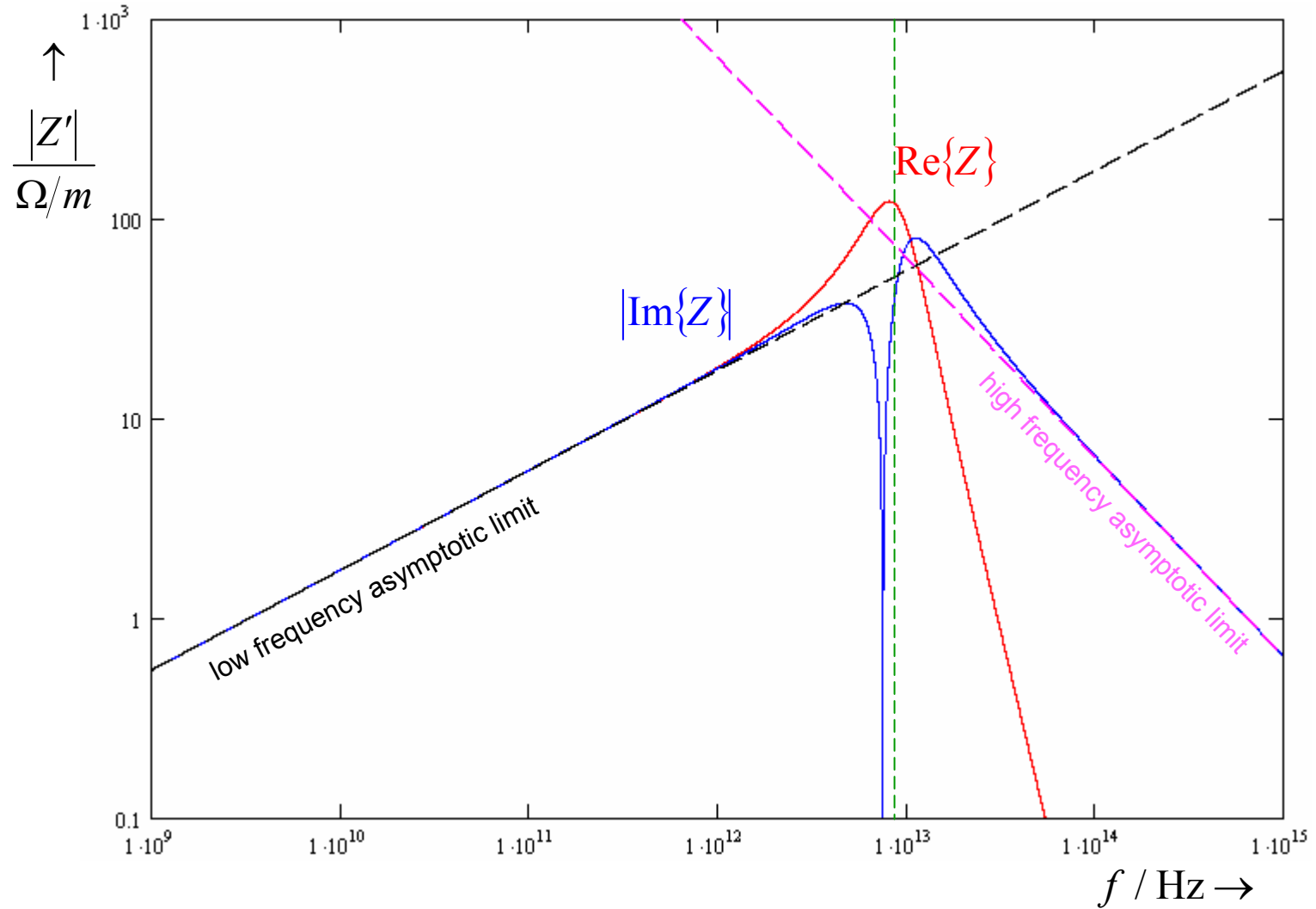
$$\tau = 2.46 \cdot 10^{-14} \text{ s}$$

$$f_{\text{ch}} = 1.02 \cdot 10^{13} \text{ Hz}$$

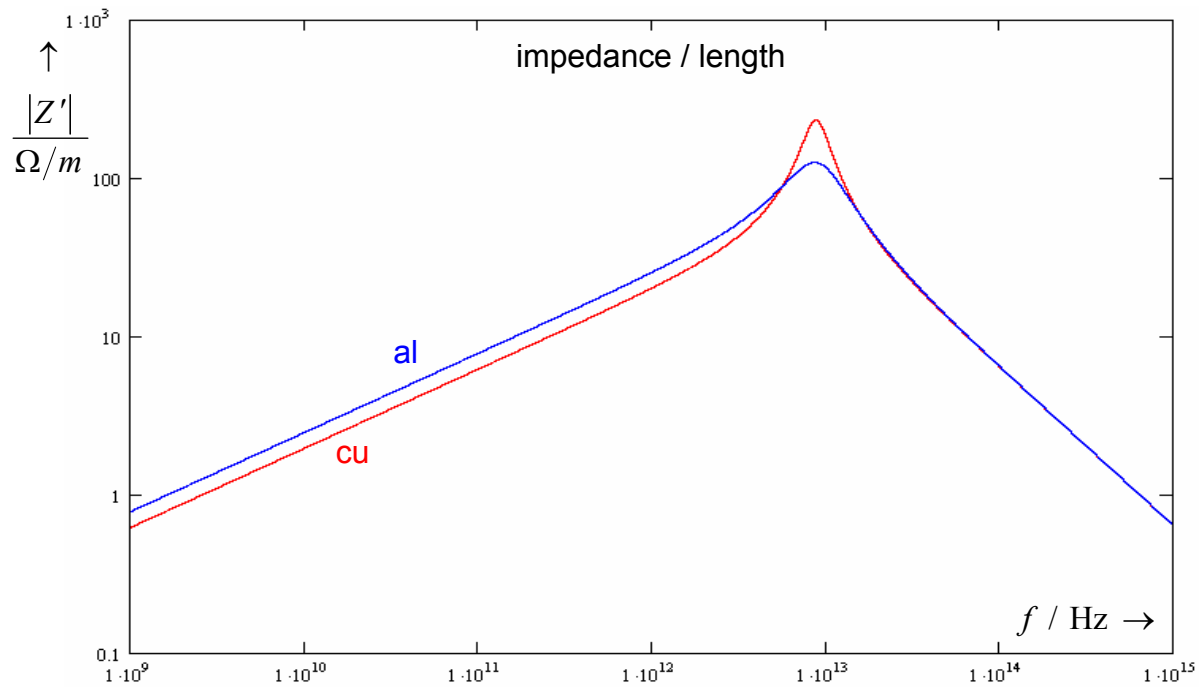


alu, R = 3mm

$$\kappa_0 = 36.6 \cdot 10^6 \frac{1}{\Omega m} \quad \tau = 0.71 \cdot 10^{-14} \text{ s} \quad f_{\text{ch}} = 0.87 \cdot 10^{13} \text{ Hz}$$

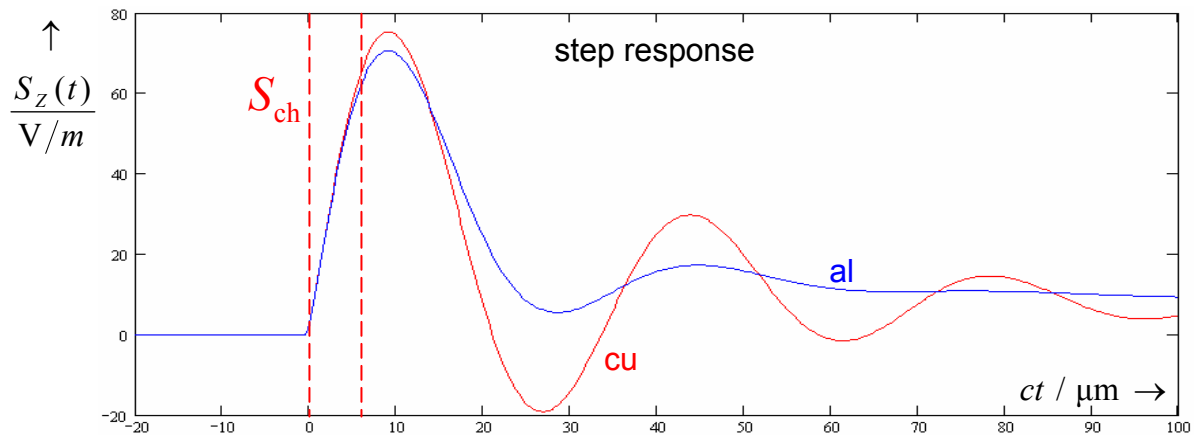


copper & alu, R = 3mm



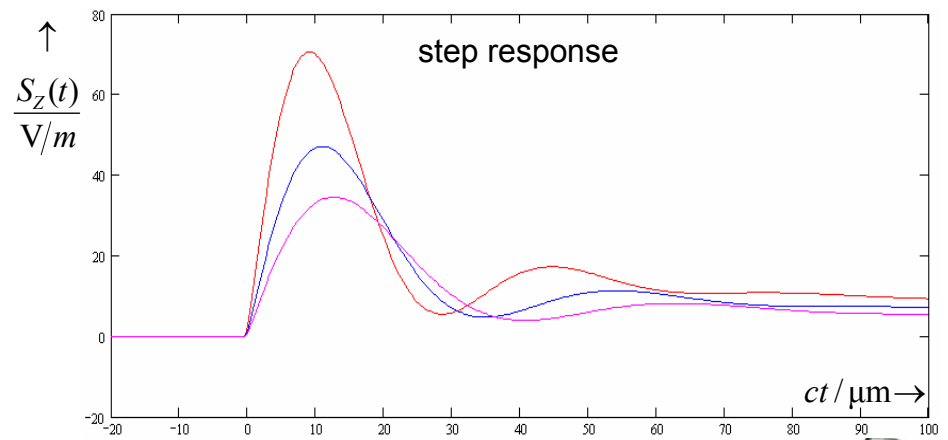
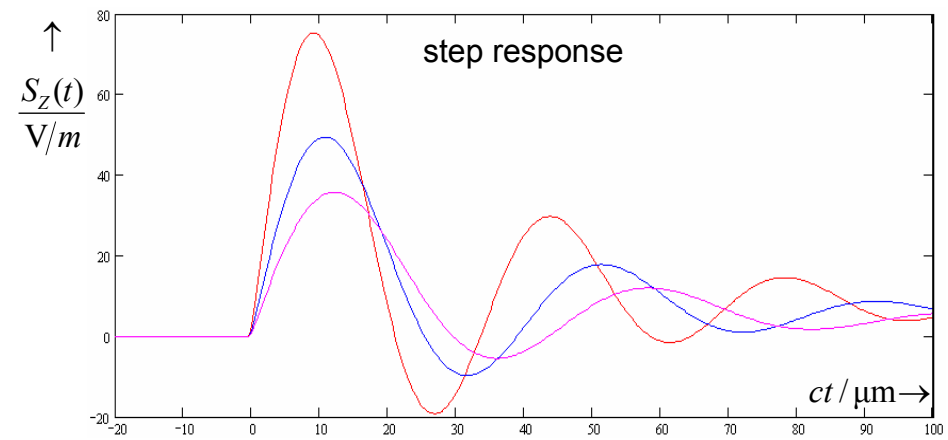
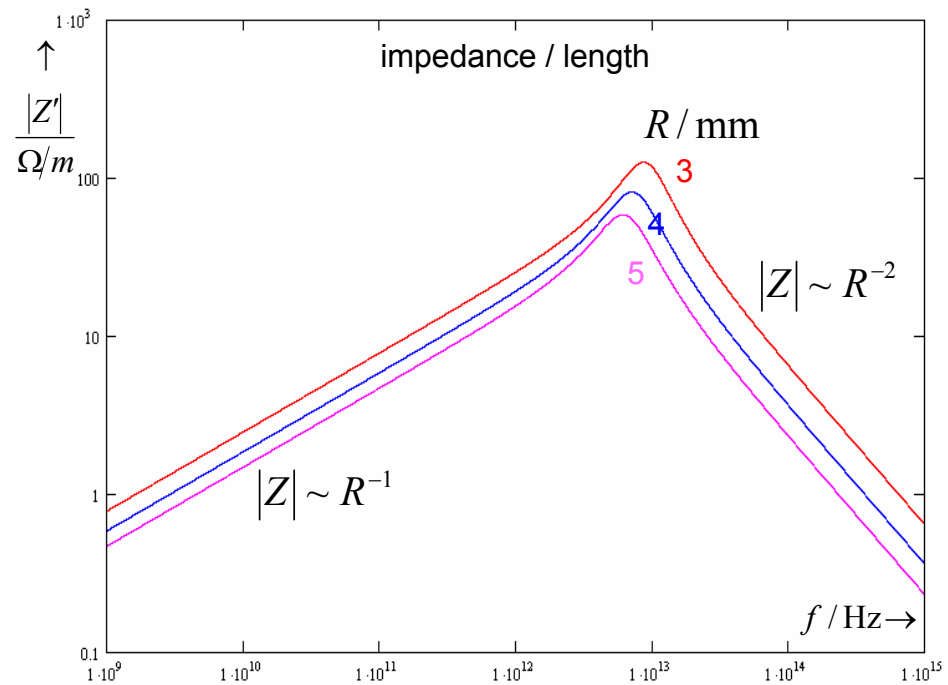
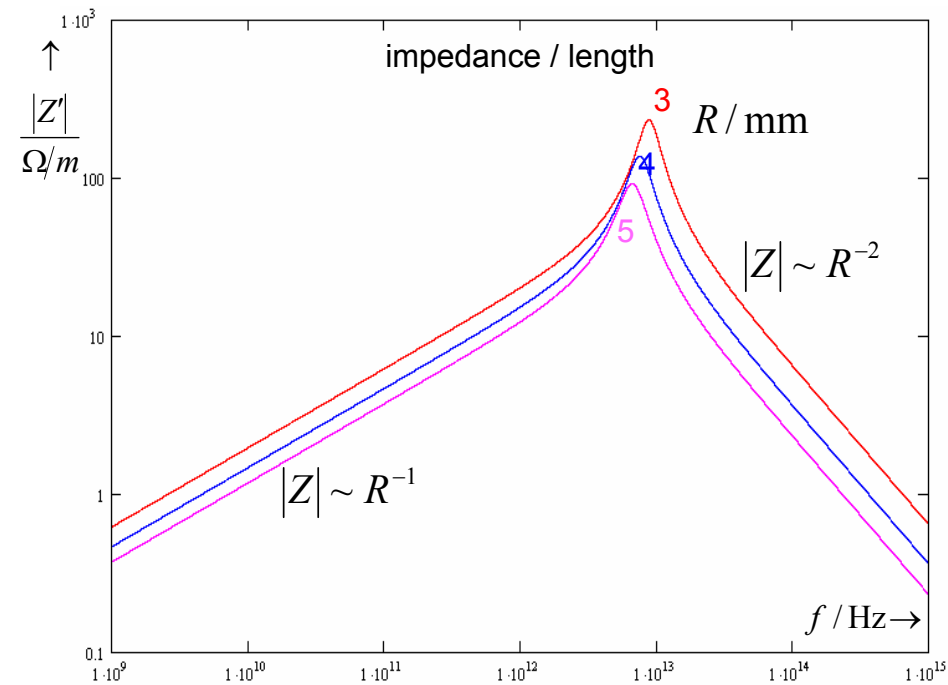
$$S(t) = \begin{cases} 0 & \text{if } t < 0 \\ 1A & \text{otherwise} \end{cases}$$

$$S_z(t) = S(t) \otimes F^{-1}\{Z'\}$$

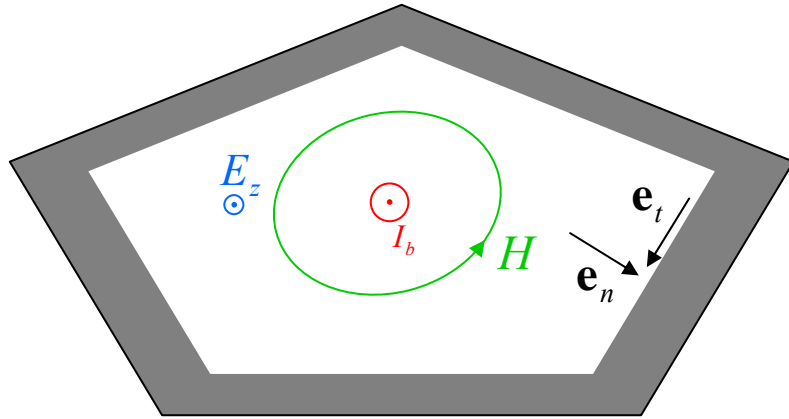


copper

alu



2d geometry: arbitrary cross-section



$$\mathbf{E} = \tilde{\mathbf{E}}(x, y) \exp(i\omega(t - z/c))$$

$$\rho = \tilde{\rho}(x, y) \exp(i\omega(t - z/c))$$

$$\mathbf{J} = \rho c \mathbf{e}_z$$

2d differential equation:

$$\nabla_t^2 \tilde{\mathbf{E}}_{\perp} = \frac{1}{\varepsilon} \nabla_t \rho$$

$$\tilde{E}_z = \frac{c}{\omega} \left(\nabla_t \tilde{\mathbf{E}}_{\perp} - \frac{\tilde{\rho}}{\varepsilon} \right)$$

boundary condition (surface impedance)

$$\tilde{E}_z = -\frac{Z_s}{Z_0} \tilde{E}_n \quad \tilde{E}_t = 0$$

beam impedance

$$Z'_b = -\left. \frac{\tilde{E}_z}{\tilde{I}_b} \right|_{\mathbf{r} \rightarrow \mathbf{r}_b}$$

more:

K. Yokoya: Resistive Wall impedance of beam pipes of general cross section

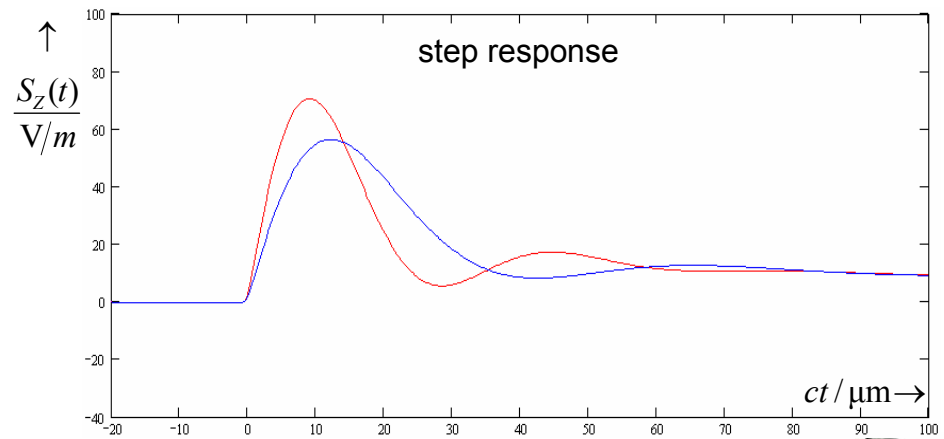
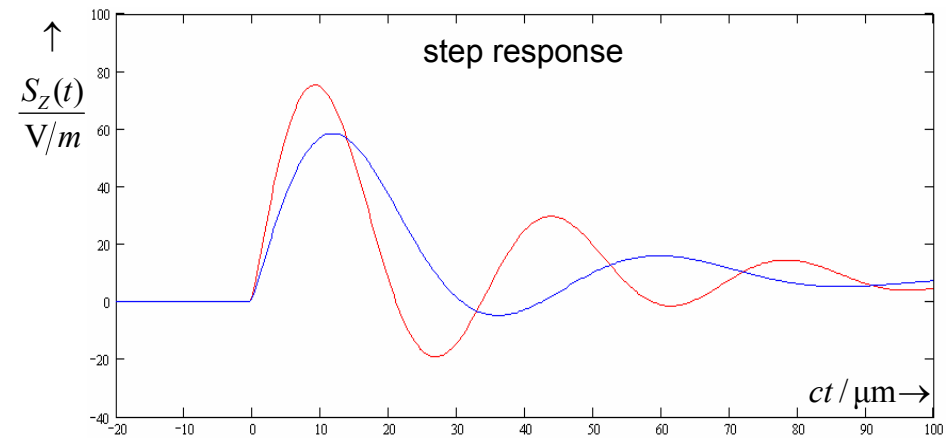
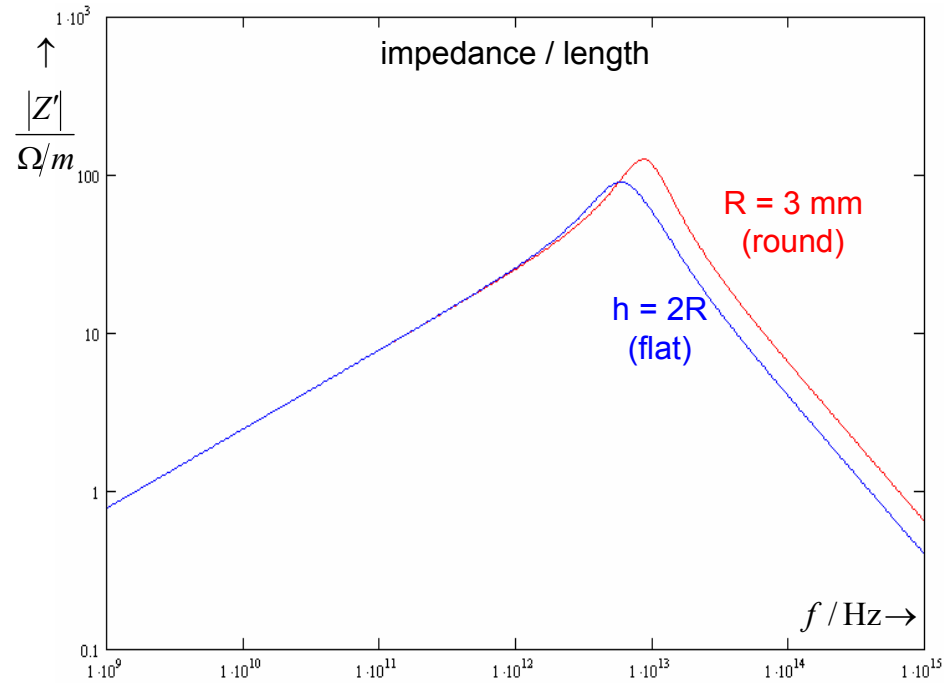
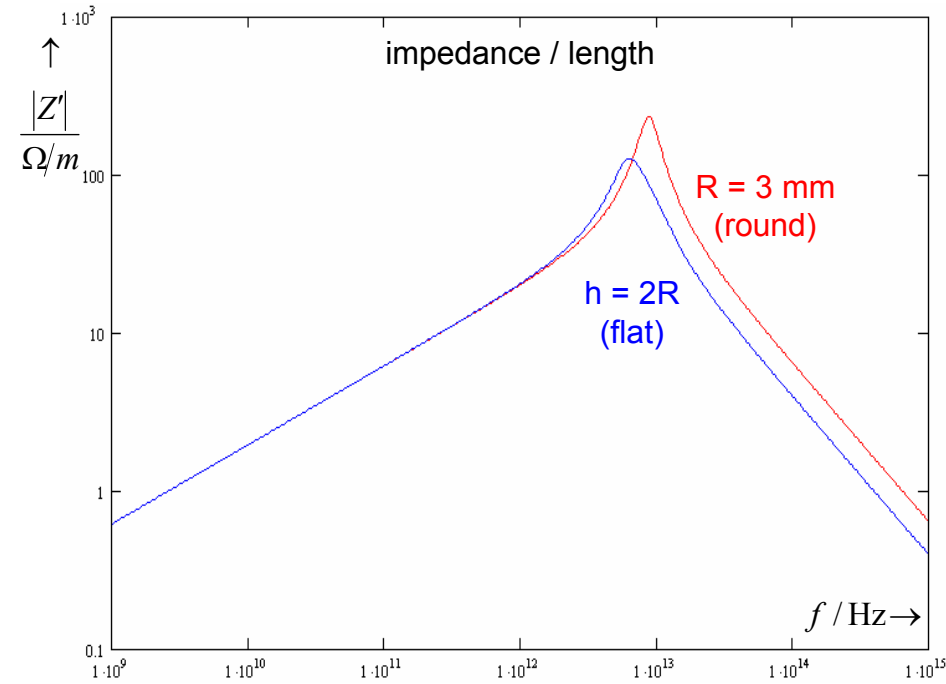
Part. Acc., 1993, Vol. 41, pp 221-248



2d geometry: flat beam pipe

copper

alu



surface: oxide layer

surface impedance of thin dielectric layer (ϵ_r) on perfect conductor:

$$Z_s^{(\epsilon)} \approx j\omega L \quad \text{with} \quad L = \Delta\mu \frac{\epsilon_r - 1}{\epsilon_r}$$
$$L \rightarrow \Delta\mu \quad \text{for} \quad \epsilon_r \gg 1$$

surface impedance of thin dielectric layer (ϵ_r) on metallic conductor (κ):

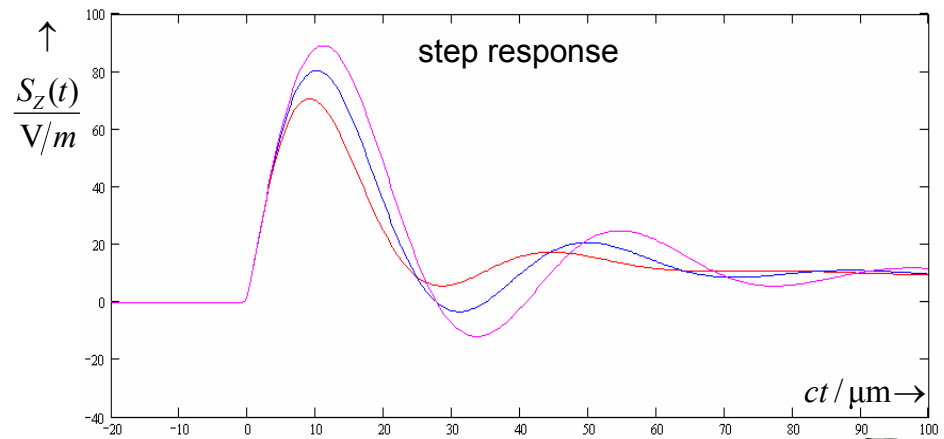
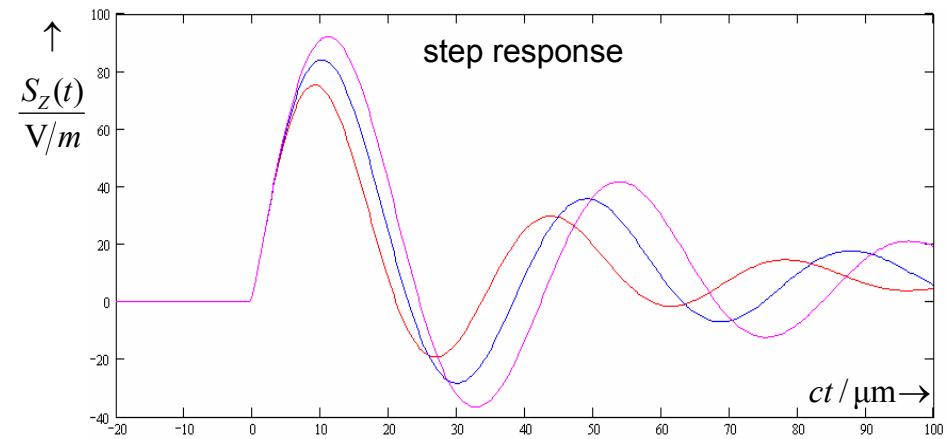
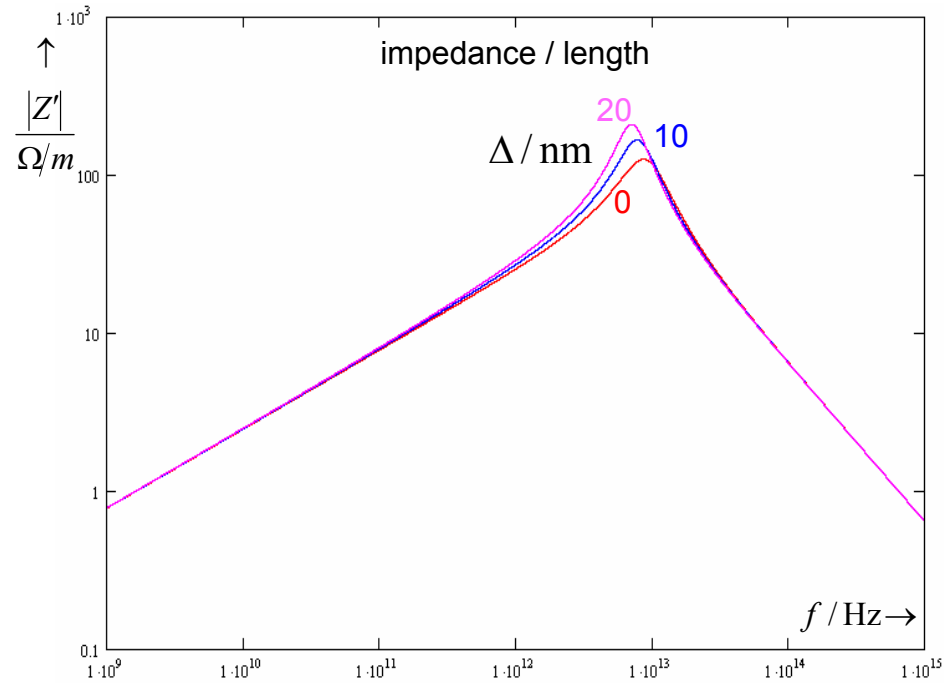
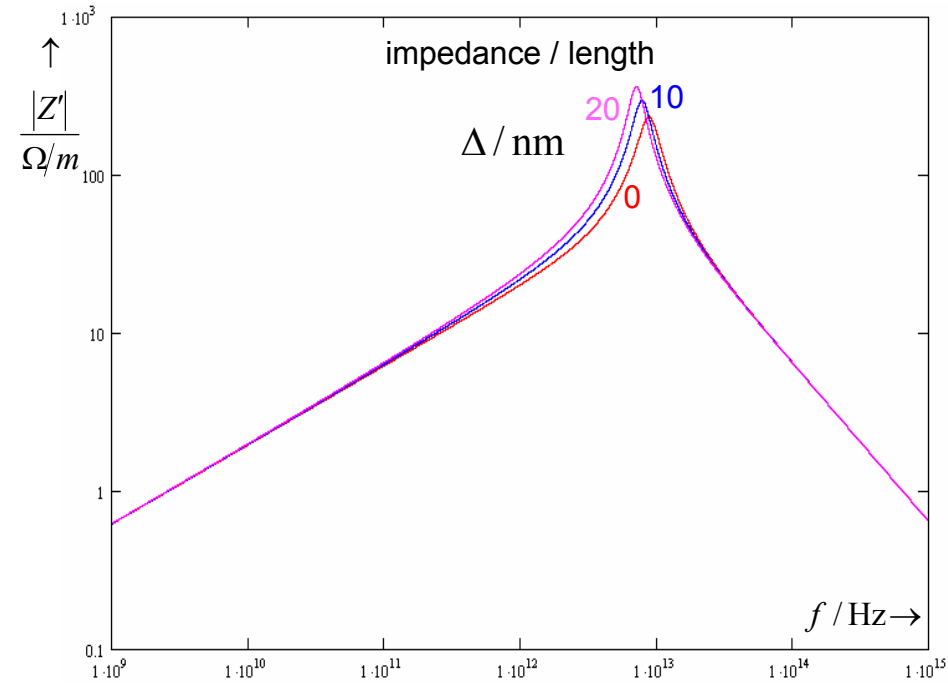
$$Z_s = Z_s^{(\kappa)} + Z_s^{(\epsilon)}$$



R=3mm & oxide layer ($\epsilon_r=2$)

copper

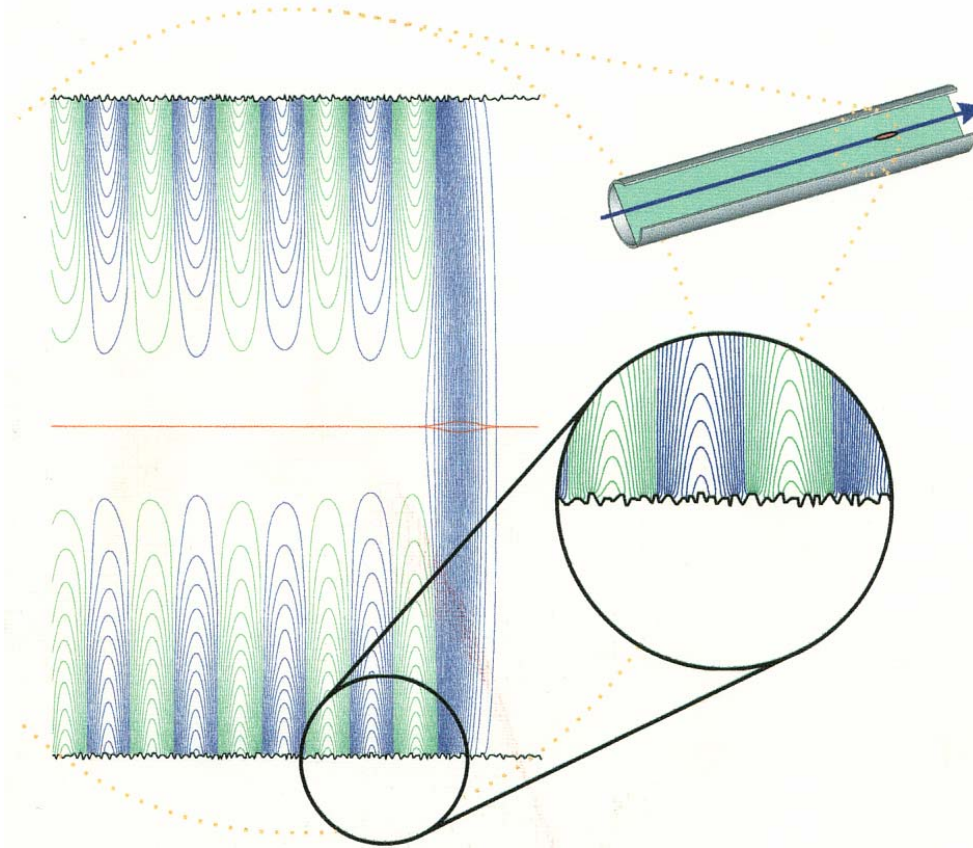
alu



surface: roughness

(very incomplete list of models)

Novokhatski, Timm, Weiland



rough surface behaves as dielectric layer
→ synchronous mode

$$Z'_b(\omega) = \frac{Z_s(\omega)}{2\pi R} \frac{1}{1 + i \frac{\omega R}{c} \frac{Z_s(\omega)}{Z_0}}$$

with $Z_s(\omega) = i\omega L$

$$L = \mu_0 \Delta_{eff} \frac{\epsilon_r - 1}{\epsilon_r}$$

$$\Delta_{eff} \approx 0.5 \Delta_{rms} \quad \epsilon_r \approx 2$$

synchronous mode:

$$1 + i \frac{\omega R}{c} \frac{Z_s(\omega)}{Z_0} = 0$$

Stupakov I $Z'_b(\omega) = \frac{i\omega L}{2\pi R}$ L from ACF of surface roughness $L \approx \mu_0 \Delta_{rms} \frac{\epsilon_r - 1}{\epsilon_r}$ $\Delta_{eff} \approx 10^{-2} \Delta_{rms}$

Stupakov II sinusoidal surface $R(z) = R_0 + \Delta \cos(2\pi z/\lambda)$ with $\Delta \ll \lambda/2\pi \rightarrow$ no synchronous mode

Dohlus sinusoidal surface, with $\Delta < \lambda/2\pi$, includes transition sync. mode \rightarrow no synchronous mode
sinusoidal & resistive surface



April 2001, TESLA 2001-26

Impedance of Beam Pipes with Smooth Shallow Corrugations

M. Dohlus

Deutsches Elektronen Synchrotron
Notkestr. 85, D-22603 Hamburg, Germany

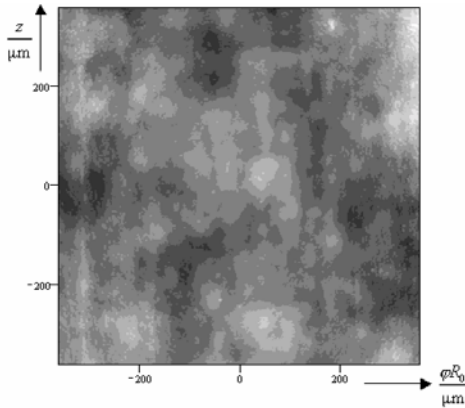


Fig. 23: Surface function $\delta_r(y, z) = \delta r(y, z) - (q_0 + q_y y + q_z z) - (q_0 + q_y y + q_z z)^2 + q_z z$ after extraction of the curvature (in azimuthal direction) and slope (in z direction). The gray scale ranges from -2 to 2.8 μm .

rms value of the roughness $\delta_{\text{rms}} = \sqrt{R_{c,2D}(0,0)} = 0.58 \mu\text{m}$

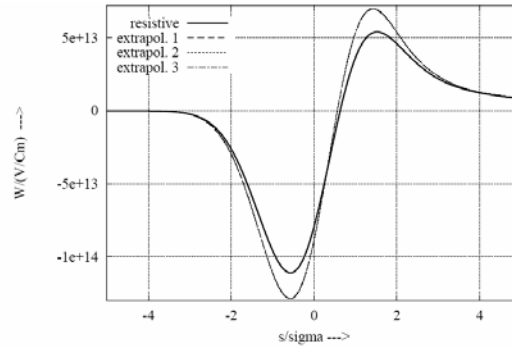


Fig. 28: Wake potential calculated by the LB-N₂nd method for three extrapolations of the ACF (thin lines), resistive wall wake (thick line) of a perfect pipe. Configuration: aluminum pipe, $R_0 = 3\text{mm}$, random surface, gaussian bunch with $\sigma = 25 \mu\text{m}$.

$R_0 = 3\text{mm}$ gaussian bunch	$\min(W^\sigma)$ V/pCm	$\max(W^\sigma)$ V/pCm	$\langle W^\sigma \rangle$ V/pCm	$\text{rms}(W^\sigma)$ V/pCm
resistive (cu)	-111	54.1	-44.9	56.7
resistive+rough	-129	69.6	-47.9	68.7

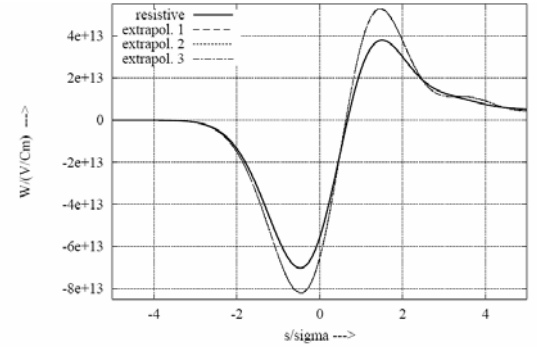
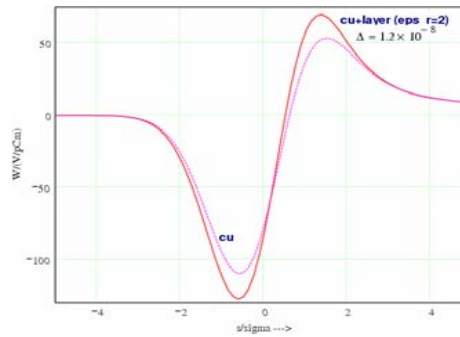


Fig. 29: Wake potential calculated by the LB-N₂nd method for three extrapolations of the ACF (thin lines), resistive wall wake (thick line) of a perfect pipe. Configuration: aluminum pipe, $R_0 = 5\text{mm}$, random surface, gaussian bunch with $\sigma = 25 \mu\text{m}$.

$R_0 = 5\text{mm}$ gaussian bunch	$\min(W^\sigma)$ V/pCm	$\max(W^\sigma)$ V/pCm	$\langle W^\sigma \rangle$ V/pCm	$\text{rms}(W^\sigma)$ V/pCm
resistive (cu)	-70.3	38.0	-29.0	36.5
resistive+rough	-82.0	52.6	-31.7	45.1



av

rms

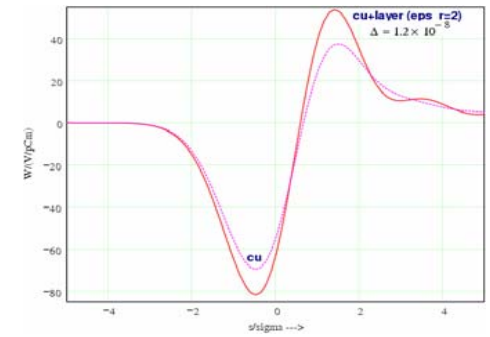
cu

$$k_{\text{cu}} = -4.441 \times 10^{13}$$

$$\text{rms}_{\text{cu}} = 5.597 \times 10^{13}$$

$$\text{cu+layer (eps_r=2)} \quad \Delta = 1.2 \times 10^{-8} \quad k = -4.559 \times 10^{13}$$

$$\text{rms} = 6.873 \times 10^{13}$$



av

rms

cu

$$k_{\text{cu}} = -2.871 \times 10^{13}$$

$$\text{rms}_{\text{cu}} = 3.602 \times 10^{13}$$

$$\text{cu+layer (eps_r=2)} \quad \Delta = 1.2 \times 10^{-8} \quad k = -3.031 \times 10^{13}$$

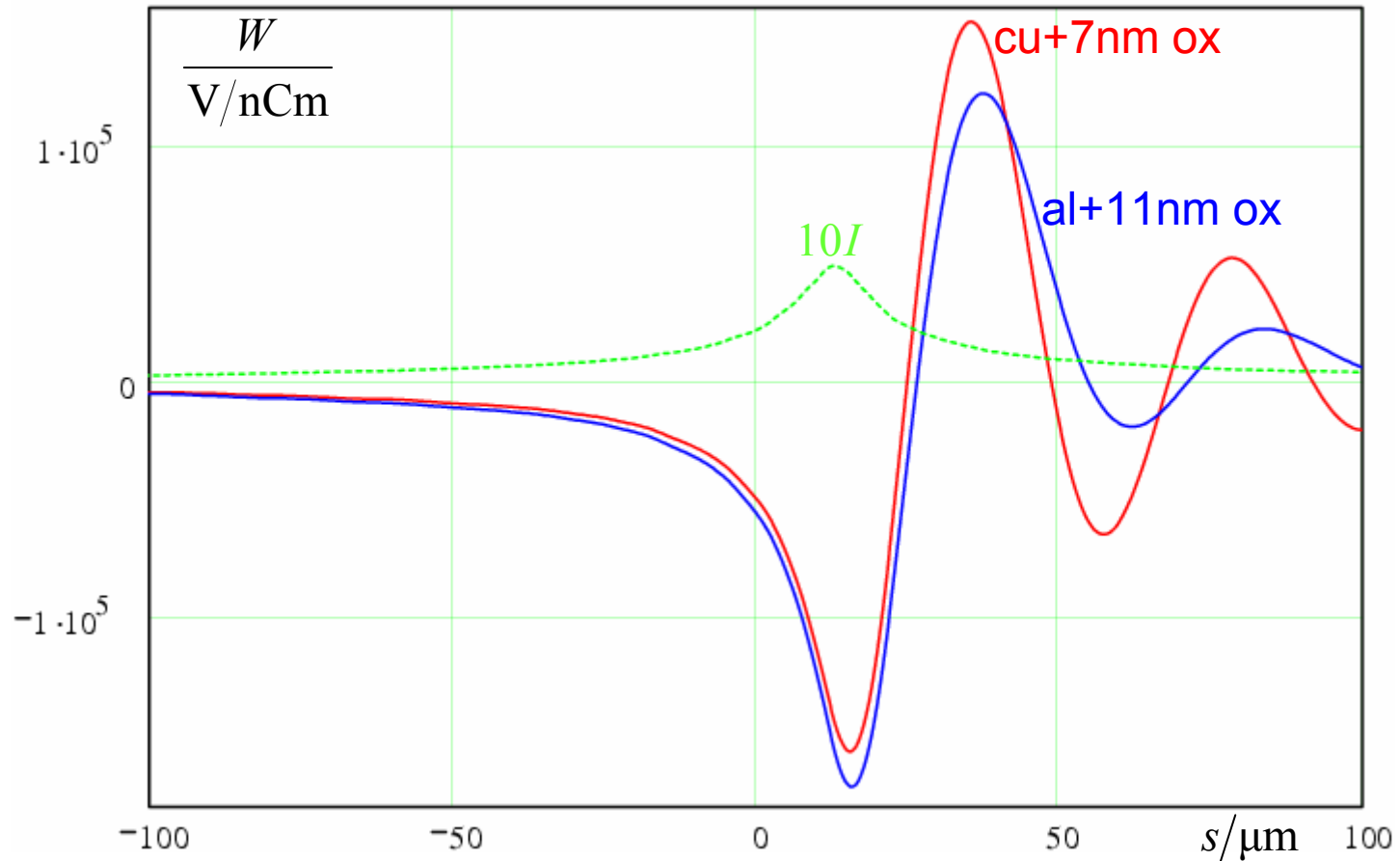
$$\text{rms} = 4.551 \times 10^{13}$$

conclusion: 0.58 μm roughness behaves similar as 12 nm $\epsilon_r = 2$ oxide layer



300nm roughness \rightarrow " \approx 6nm oxide layer, $\epsilon_r=2$ "

$$R_{\text{pipe}} = 3.8 \text{ mm}$$



cu: 7nm ox = 1nm (real oxide) + 6nm (roughness)

al: 11nm ox = 5nm (real oxide) + 6nm (roughness)

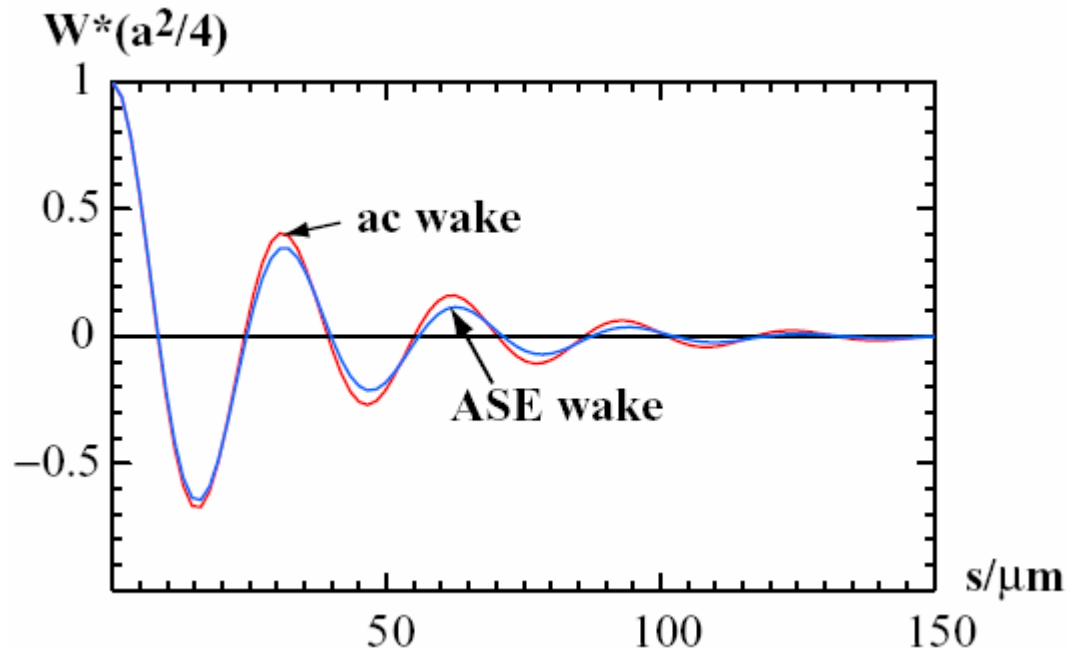


surface: anomalous skin effect

'ac' conductivity of copper: $\kappa(\omega) \approx \frac{\kappa_0}{1+i\omega\tau}$ $\kappa_0 = 58 \cdot 10^6 \frac{1}{\Omega\text{m}}$ $\tau = 2.46 \cdot 10^{-14} \text{s}$

Resistive wall wakefield in the LCLS undulator, Bane, Stupakov; SLAC-PUB-11227, May 2005

round pipe, $R = 2.5\text{mm}$, δ -wake



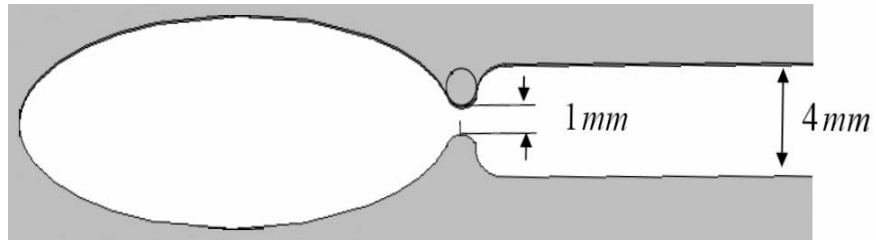
'ac' conductivity causes a slight overestimation



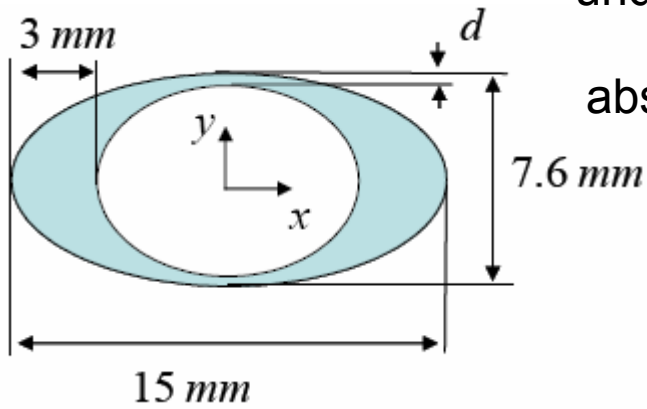
3d geometry

European XFEL

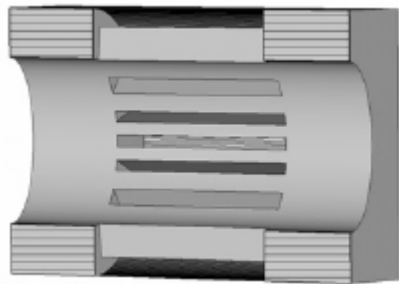
TESLA-FEL 2005-10



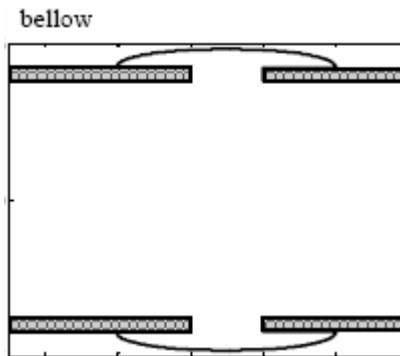
undulator pipe



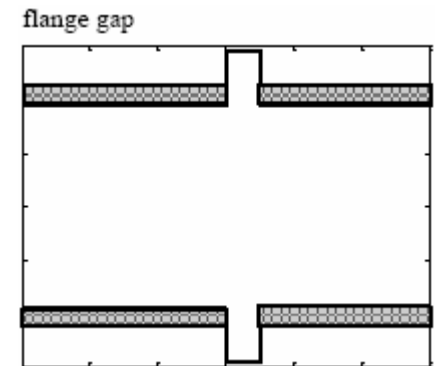
absorber



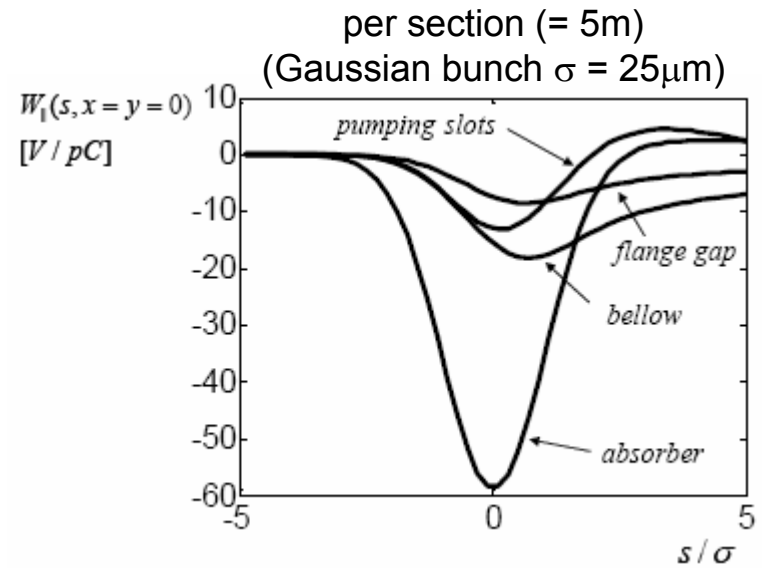
pump slots



bellow



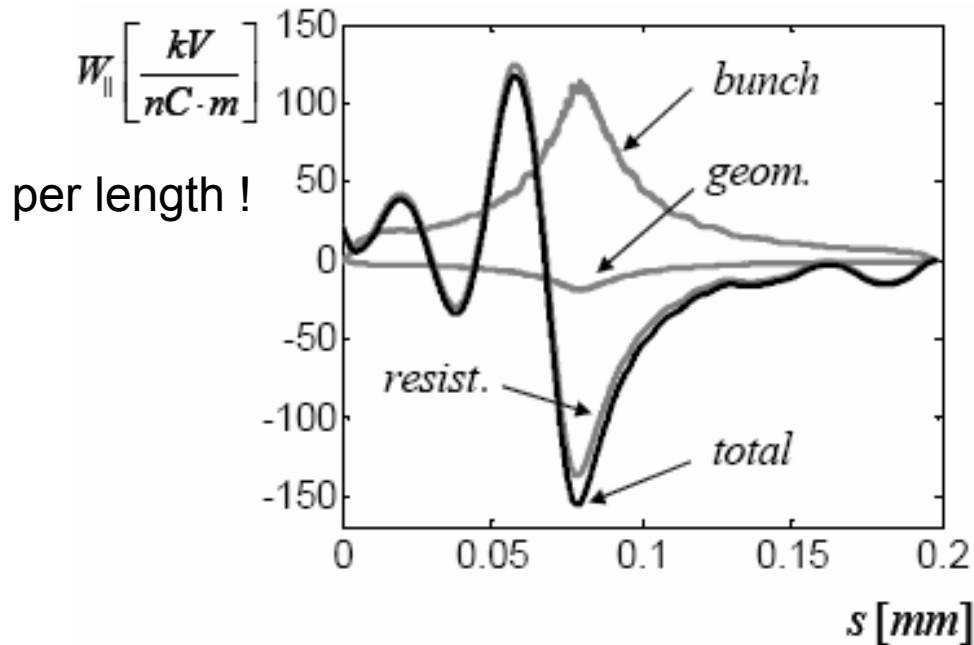
flange gap



wakes in European XFEL

per section (= 5m)
(Gaussian bunch $\sigma = 25\mu\text{m}$)

	Loss, V/pC	Spread, V/pC	Peak, V/pC
absorber	42	16	-58
pumping slot (Fig.4)	<0.2	<0.1	>-0.3
pump (Fig.7)	9	4	-13
bellow	13	5	-18
flange gap	6	2.4	-8.5
Total geom.	70	25	-95



resistive wake
of **round** pipe !



collimator wakes

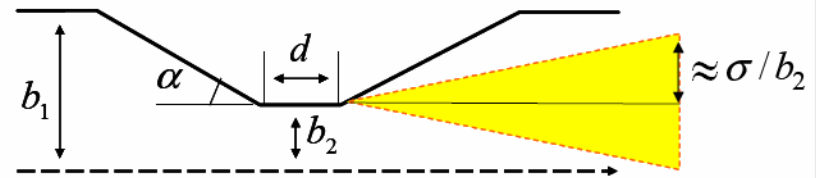
Igor Zagorodnov

http://www.desy.de/xfel-beam/data/talks/talks/zagorodnov_-_colli_wakes_20060925.pdf

Outline

- Round collimators
 - Inductive regime
 - Diffractive regime
 - Near wall wakefields
 - Resistive wakefields
- 3D collimators (rectangular, elliptical)
 - Diffractive regime
 - Inductive regime
- Simulation of SLAC experiments
- XFEL collimators
 - Effect of tapering and form optimization
 - Kick dependence on collimator length

Round collimator. Regimes



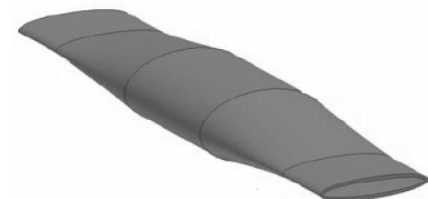
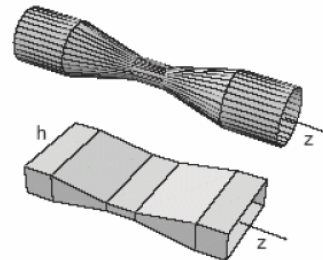
Top half of a symmetric collimator.

Inductive

$$\rho_1 \equiv \alpha b_2 \sigma^{-1} < 1$$

Diffractive

$$\rho_1 > 1$$



wakes (codes)

ECHO	2d,3d	no dispersion	indirect w-integration	conf. mesh	
CST-MWS	3d	dispersion	(indirect w-integration)	conf. mesh	
ABCI	2d	dispersion	indirect w-integration	staircase	
MAFIA	2d/3d	dispersion	(indirect w-integration)	staircase+	
GdfidL	3d	dispersion	indirect w-integration	staircase+	?
PBCI	3d	no dispersion	indirect w-integration	staircase	parallel
VORPAL	3d	dispersion		conf. mesh	parallel
Tau3P	3d	dispersion		conf. mesh	parallel
more		no dispersion			

$$L\delta_z^2 > \sigma^3 \quad \text{FDTD not sufficient}$$

(L = length of field calculation,
 δz = step width of mesh
 σ = rms bunch length)



summary

bunch shape: if: $\sigma \gg S_{\text{ch}}$ $Z'_b(\omega) \approx \frac{1}{2\pi R} \sqrt{\frac{i\omega\mu}{\kappa_0}} \rightarrow w \propto \frac{1}{R\sqrt{\sigma\kappa_0}}$

surface effects: roughness $\Delta_r \rightarrow$ dielectric layer $\Delta_d \approx \Delta_r/50$, $\epsilon_r = 2$ } $\approx 10\%$
dielectric layer \rightarrow inductive surface impedance }
conductivity \rightarrow surface impedance $\approx \sqrt{i\omega\mu/\kappa_0}$ $\approx 90\%$
effective surface impedance = superposition of surface imp.

round pipe: transformation to beam impedance $Z'_b = \frac{Z_s}{2\pi R} \left(1 + i \frac{\omega R Z_s}{c 2 Z_0} \right)^{-1}$

flat pipe: effects are overestimated by round pipe

geometric wakes: **small compared to surface effects (for European XFEL)**

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